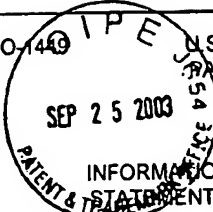


Form PTO-1449 	ATTY. DOCKET NO.	SERIAL NO.
	YOR920000655US2 (8728-446 DIV)	10/606,523
	APPLICANT	
	Alessandro C. Callegari et al.	
FILING DATE		GROUP ART UNIT
June 26, 2003		1762

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>MP</i>	5,030,322	7/9/91	Shimada et al.	156	655	8/17/90
	5,710,608	1/20/98	Nakabayashi et al.	349	125	12/27/95
	5,770,826	6/23/98	Chaudhari et al.	204	157.15	5/10/96
	6,020,946	2/1/00	Callegari et al.	349	124	2/23/98
	6,061,114	5/9/00	Callegari et al.	349	125	2/23/98
	6,061,115	5/9/00	Samant et al.	349	129	11/3/98
	6,331,381	12/18/01	Chaudhari et al.	430	320	4/14/00
<i>MP</i>	6,485,614	11/26/02	Kato et al.	204	157.15	11/30/00

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO


OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>MP</i>	Tschersich, K.G., et al., <u>Formation of an Atomic Hydrogen Beam by a Hot Capillary</u> , Journal of Applied Physics, Vol. 84, No. 8, 10/15/98, pp. 4065-4070.
<i>MP</i>	Harvey, K.C., et al., <u>Semiconductor Detector for the Selective Detection of Atomic Hydrogen</u> , American Institute of Physics, pp. 1117-1120. 1983 (no month)

EXAMINER <i>MP</i>	DATE CONSIDERED <i>3/20/05</i>
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* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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Form PTO-1449  U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)	ATTY. DOCKET NO.	SERIAL NO.
	YOR920000655US2 (8728-446 DIV)	10/606,523
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FOREIGN PATENT DOCUMENTS

DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
					YES	NO

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>My</i>		IBM Disclosure Bulletin, Ion Bombardment of Polyimide for the Alignment of Liquid Crystals, New York, Vol. 23, No. 4B, 9/1/91, pp. 80-82.
<i>fr</i>		Japanese Abstract No. XP-002224303, 2/28/92 to Seiko Epson Corp. for JP4063323A <i>Feb 1992</i> <i>published 2-1992</i>
		U.S. Patent Application Publication No. 2002/0001057, Publication Date Jan. 3, 2002, <u>Method and Apparatus for Making a Crystal Alignment Layer</u>
		U.S. Patent Application Publication No. 2001/0025826, Publication Date Oct. 4, 2001, <u>Dense-Plasma Etching of INP-Based Materials Using Chlorine and Nitrogen</u>
<i>My</i>		U.S. Patent Application Publication No. 2001/0041380, Publication Date Nov. 15, 2001, <u>Method for Forming a Multi-Domain Alignment Layer for a Liquid Crystal Display Device.</u>

EXAMINER	DATE CONSIDERED
<i>My</i>	<i>3/24/05</i>
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